

#### ISSUED DATE: 10/09/2007

## 9.20-10.00 GHz 8-Watt Internally Matched Power FET

## **FEATURES**

- 9.20-10.0GHz Bandwidth
- Input/Output Impedance Matched to 50 Ohms
- +39.0 dBm Output Power at 1dB Compression
- 7.5 dB Power Gain at 1dB Compression
- 30% Power Added Efficiency
- -46 dBc IM3 at PO = 28dBm SCL
- Hermetic Metal Flange Package
- 100% Tested for DC, RF, and R<sub>TH</sub>

## ELECTRICAL CHARACTERISTICS ( $T_a = 25^{\circ}C$ )



Caution! ESD sensitive device.

**EIC0910A-8** 

SYMBOL	PARAMETERS/TEST CONDITIONS <sup>1</sup>	MIN	ТҮР	MAX	UNITS				
P <sub>1dB</sub>	Output Power at 1dB Compressionf = 9.20-10.0GHz $V_{DS}$ = 10 V, $I_{DSQ} \approx 2200$ mA	38.5	39.0		dBm				
G <sub>1dB</sub>	Gain at 1dB Compressionf = 9.20-10.0GHz $V_{DS}$ = 10 V, $I_{DSQ} \approx 2200$ mA	6.5	7.5		dB				
∆G	Gain Flatnessf = 9.20-10.0GHz $V_{DS}$ = 10 V, $I_{DSQ} \approx 2200$ mA			±0.6	dB				
PAE	Power Added Efficiency at 1dB Compression $V_{DS}$ = 10 V, $I_{DSQ} \approx 2200$ mAf = 9.20-10.0GHz		30		%				
Id <sub>1dB</sub>	Drain Current at 1dB Compression f = 9.20-10.0GHz		2300	2600	mA				
IM3	Output 3rd Order Intermodulation Distortion $\Delta f$ = 10 MHz 2-Tone Test; Pout = 28dBm S.C.L <sup>2</sup> $V_{DS}$ = 10 V, $I_{DSQ} \approx 65\%$ IDSSf = 10.0GHz	-43	-46		dBc				
I <sub>DSS</sub>	Saturated Drain Current $V_{DS}$ = 3 V, $V_{GS}$ = 0 V		4000	5000	mA				
V <sub>P</sub>	Pinch-off Voltage $V_{DS}$ = 3 V, $I_{DS}$ = 40 mA		-2.5	-4.0	V				
R <sub>TH</sub>	Thermal Resistance <sup>3</sup>		3.5	4.0	°C/W				

Note: 1. Tested with 100 Ohm gate resistor.

2. S.C.L. = Single Carrier Level.

3. Overall Rth depends on case mounting.

## ABSOLUTE MAXIMUM RATING<sup>1,2</sup>

SYMBOLS	PARAMETERS	ABSOLUTE <sup>1</sup>	CONTINUOUS <sup>2</sup>
Vds	Drain-Source Voltage	15V	10V
Vgs	Gate-Source Voltage	-5V	-4.5V
lgsf	Forward Gate Current	96mA	28.8mA
lgsr	Reserve Gate Current	-19.2mA	-4.8mA
Pin	Input Power	38.5dBm	@ 3dB Compression
Tch	Channel Temperature	175 °C	175 °C
Tstg	Storage Temperature	-65 to +175 °C	-65 to +175 °C
Pt	Total Power Dissipation	38W	38W

Note: 1. Exceeding any of the above ratings may result in permanent damage.

2. Exceeding any of the above ratings may reduce MTTF below design goals.

Specifications are subject to change without notice. Excelics Semiconductor, Inc. 310 De Guigne Drive, Sunnyvale, CA 94085 Phone: 408-737-1711 Fax: 408-737-1868 Web: <u>www.excelics.com</u>

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# EIC0910A-8

EIC0910A-8NH (Non-Hermetic)

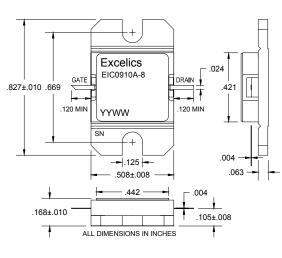
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## PACKAGES OUTLINE

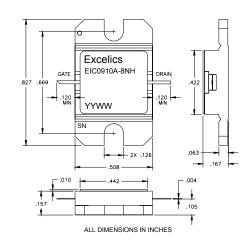
Dimensions in inches, Tolerance + .005 unless otherwise specified

## EIC0910A-8 (Hermetic)





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## ORDERING INFORMATION

Part Number	Packages	Grade <sup>1</sup>	f <sub>Test</sub> (GHz)	P <sub>1dB</sub> (min)	IM <sub>3</sub> (min) <sup>2</sup>
EIC0910A-8	Hermetic	Industrial	9.20-10.00GHz	38.5	-43
EIC0910A-8NH	Non-Hermetic	Industrial	9.20-10.00GHz	38.5	-43

Notes: 1. Contact factory for military and hi-rel grades.

2. Exact test conditions are specified in "Electrical Characteristics" table.

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness